Web of Science™

1 record(s) printed from Clarivate Web of Science

Record 1 of 1

Title: A Closer Look at Real-World Patches

Author(s): Liu, K (Liu, Kui); Kim, D (Kim, Dongsun); Koyuncu, A (Koyuncu, Anil); Li, L (Li, Li); Bissyande, TF (Bissyande, Tegawende F.); Le Traon, Y (Le Traon, Yves)

Book Group Author(s): IEEE

Source: PROCEEDINGS 2018 IEEE INTERNATIONAL CONFERENCE ON SOFTWARE MAINTENANCE AND EVOLUTION (ICSME) **Book Series:** Proceedings-IEEE International Conference on Software Maintenance **Pages:** 275-286 **DOI:** 10.1109/ICSME.2018.00037 **Published:** 2018

Accession Number: WOS:000451376200025

Conference Title: IEEE International Conference on Software Maintenance and Evolution (ICSME)

Conference Date: SEP 23-29, 2018

Conference Location: Madrid, SPAIN

Conference Sponsors: IEEE, IEEE Comp Soc

Author Identifiers:

Author	Web of Science ResearcherID	ORCID Number
Koyuncu, Anil	AAA-5382-2021	0000-0001-6975-6752
Li, Li	AAR-3316-2020	
LE TRAON, Yves	T-2911-2019	
Kim, Dongsun	B-4856-2015	0000-0003-0272-6860
LE TRAON, Yves		0000-0002-1045-4861

ISSN: 1063-6773

ISBN: 978-1-5386-7870-1

End of File